Abstract

To detect a defect formed in a coating layer in a workpiece including a variable density layer having a variable density pattern and the coating layer, which covers the variable density pattern of the variable density layer, illumination light emitted from an illuminator has a wavelength at which an intensity of light that is reflected or scattered from the coating layer to enter an image pickup device is higher than an intensity of light that is reflected from at least the variable density layer to enter the image pickup device. Thus, the illumination light reduces influence of the variable density pattern of the variable density layer.